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Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Product Status	Active
Number of LABs/CLBs	37200
Number of Logic Elements/Cells	476160
Total RAM Bits	39223296
Number of I/O	600
Number of Gates	-
Voltage - Supply	0.95V ~ 1.05V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	1156-BBGA, FCBGA
Supplier Device Package	1156-FCBGA (35x35)
Purchase URL	https://www.e-xfl.com/product-detail/xilinx/xc6vsx475t-1ff1156c

Table 3: DC Characteristics Over Recommended Operating Conditions (1)(2)

Symbol	Description	Min	Typ	Max	Units
V_{DRINT}	Data retention V_{CCINT} voltage (below which configuration data might be lost)	0.75	–	–	V
V_{DRI}	Data retention V_{CCAUX} voltage (below which configuration data might be lost)	2.0	–	–	V
I_{REF}	V_{REF} leakage current per pin	–	–	10	μA
I_L	Input or output leakage current per pin (sample-tested)	–	–	10	μA
$C_{IN}^{(3)}$	Die input capacitance at the pad	–	–	8	pF
I_{RPU}	Pad pull-up (when selected) @ $V_{IN} = 0V$, $V_{CCO} = 2.5V$	20	–	80	μA
	Pad pull-up (when selected) @ $V_{IN} = 0V$, $V_{CCO} = 1.8V$	8	–	40	μA
	Pad pull-up (when selected) @ $V_{IN} = 0V$, $V_{CCO} = 1.5V$	5	–	30	μA
	Pad pull-up (when selected) @ $V_{IN} = 0V$, $V_{CCO} = 1.2V$	1	–	20	μA
I_{RPD}	Pad pull-down (when selected) @ $V_{IN} = 2.5V$	3	–	80	μA
I_{BATT}	Battery supply current	–	–	150	nA
n	Temperature diode ideality factor	–	1.0002	–	n
r	Series resistance	–	5	–	Ω

Notes:

1. Typical values are specified at nominal voltage, 25°C.
2. Maximum value specified for worst case process at 25°C.
3. This measurement represents the die capacitance at the pad, not including the package.

Important Note

Typical values for quiescent supply current are specified at nominal voltage, 85°C junction temperatures (T_j). Xilinx recommends analyzing static power consumption at $T_j = 85^\circ\text{C}$ because the majority of designs operate near the high end of the commercial temperature range. Quiescent supply current is specified by speed grade for Virtex-6 devices. Use the XPower™ Estimator (XPE) spreadsheet tool (download at <http://www.xilinx.com/power>) to calculate static power consumption for conditions other than those specified in Table 4.

Table 4: Typical Quiescent Supply Current

Symbol	Description	Device	Speed and Temperature Grade						Units
			-3 (C)	-2 (C, E, & I)	-1 (C & I)	-1 (I & M) ⁽²⁾	-1L (C)	-1L (I) ⁽¹⁾	
I_{CCINTQ}	Quiescent V_{CCINT} supply current	XC6VLX75T	927	927	927	N/A	656	741	mA
		XC6VLX130T	1563	1563	1563	N/A	1102	1245	mA
		XC6VLX195T	2059	2059	2059	N/A	1441	1628	mA
		XC6VLX240T	2478	2478	2478	N/A	1733	1957	mA
		XC6VLX365T	3001	3001	3001	N/A	2092	2363	mA
		XC6VLX550T ⁽³⁾	N/A	4515	4515	N/A	3147	3555	mA
		XC6VLX760 ⁽³⁾	N/A	5094	5094	N/A	3471	3921	mA
		XC6VSX315T	3476	3476	3476	N/A	2409	2721	mA
		XC6VSX475T ⁽³⁾	N/A	5227	5227	N/A	3622	4091	mA
		XC6VHX250T	2906	2906	2906	N/A	N/A	N/A	mA
		XC6VHX255T	2746	2746	2746	N/A	N/A	N/A	mA
		XC6VHX380T ⁽⁴⁾	4160	4160	4160	N/A	N/A	N/A	mA
		XC6VHX565T ⁽⁵⁾	N/A	5207	5207	N/A	N/A	N/A	mA
		XQ6VLX130T	N/A	1563	N/A	1563	N/A	1245	mA
		XQ6VLX240T	N/A	2478	N/A	2478	N/A	1957	mA
		XQ6VLX550T ⁽⁷⁾	N/A	N/A	N/A	4515	N/A	3555	mA
		XQ6VSX315T	N/A	3476	N/A	3476	N/A	2721	mA
		XQ6VSX475T ⁽⁷⁾	N/A	N/A	N/A	5227	N/A	4091	mA

Table 6: Power Supply Ramp Time

Symbol	Description	Ramp Time	Units
V_{CCINT}	Internal supply voltage relative to GND	0.20 to 50.0	ms
V_{CCO}	Output drivers supply voltage relative to GND	0.20 to 50.0	ms
V_{CCAUX}	Auxiliary supply voltage relative to GND	0.20 to 50.0	ms

SelectIO™ DC Input and Output Levels

Values for V_{IL} and V_{IH} are recommended input voltages. Values for I_{OL} and I_{OH} are guaranteed over the recommended operating conditions at the V_{OL} and V_{OH} test points. Only selected standards are tested. These are chosen to ensure that all standards meet their specifications. The selected standards are tested at a minimum V_{CCO} with the respective V_{OL} and V_{OH} voltage levels shown. Other standards are sample tested.

Table 7: SelectIO DC Input and Output Levels

I/O Standard	V_{IL}		V_{IH}		V_{OL}	V_{OH}	I_{OL}	I_{OH}
	V, Min	V, Max	V, Min	V, Max	V, Max	V, Min	mA	mA
LVC MOS25, LVDCI25	-0.3	0.7	1.7	$V_{CCO} + 0.3$	0.4	$V_{CCO} - 0.4$	Note(3)	Note(3)
LVC MOS18, LVDCI18	-0.3	35% V_{CCO}	65% V_{CCO}	$V_{CCO} + 0.3$	0.45	$V_{CCO} - 0.45$	Note(4)	Note(4)
LVC MOS15, LVDCI15	-0.3	35% V_{CCO}	65% V_{CCO}	$V_{CCO} + 0.3$	25% V_{CCO}	75% V_{CCO}	Note(4)	Note(4)
LVC MOS12	-0.3	35% V_{CCO}	65% V_{CCO}	$V_{CCO} + 0.3$	25% V_{CCO}	75% V_{CCO}	Note(5)	Note(5)
HSTL I ₁₂	-0.3	$V_{REF} - 0.1$	$V_{REF} + 0.1$	$V_{CCO} + 0.3$	25% V_{CCO}	75% V_{CCO}	6.3	6.3
HSTL I ⁽²⁾	-0.3	$V_{REF} - 0.1$	$V_{REF} + 0.1$	$V_{CCO} + 0.3$	0.4	$V_{CCO} - 0.4$	8	-8
HSTL II ⁽²⁾	-0.3	$V_{REF} - 0.1$	$V_{REF} + 0.1$	$V_{CCO} + 0.3$	0.4	$V_{CCO} - 0.4$	16	-16
HSTL III ⁽²⁾	-0.3	$V_{REF} - 0.1$	$V_{REF} + 0.1$	$V_{CCO} + 0.3$	0.4	$V_{CCO} - 0.4$	24	-8
DIFF HSTL I ⁽²⁾	-0.3	50% $V_{CCO} - 0.1$	50% $V_{CCO} + 0.1$	$V_{CCO} + 0.3$	—	—	—	—
DIFF HSTL II ⁽²⁾	-0.3	50% $V_{CCO} - 0.1$	50% $V_{CCO} + 0.1$	$V_{CCO} + 0.3$	—	—	—	—
SSTL2 I	-0.3	$V_{REF} - 0.15$	$V_{REF} + 0.15$	$V_{CCO} + 0.3$	$V_{TT} - 0.61$	$V_{TT} + 0.61$	8.1	-8.1
SSTL2 II	-0.3	$V_{REF} - 0.15$	$V_{REF} + 0.15$	$V_{CCO} + 0.3$	$V_{TT} - 0.81$	$V_{TT} + 0.81$	16.2	-16.2
DIFF SSTL2 I	-0.3	50% $V_{CCO} - 0.15$	50% $V_{CCO} + 0.15$	$V_{CCO} + 0.3$	—	—	—	—
DIFF SSTL2 II	-0.3	50% $V_{CCO} - 0.15$	50% $V_{CCO} + 0.15$	$V_{CCO} + 0.3$	—	—	—	—
SSTL18 I	-0.3	$V_{REF} - 0.125$	$V_{REF} + 0.125$	$V_{CCO} + 0.3$	$V_{TT} - 0.47$	$V_{TT} + 0.47$	6.7	-6.7
SSTL18 II	-0.3	$V_{REF} - 0.125$	$V_{REF} + 0.125$	$V_{CCO} + 0.3$	$V_{TT} - 0.60$	$V_{TT} + 0.60$	13.4	-13.4
DIFF SSTL18 I	-0.3	50% $V_{CCO} - 0.125$	50% $V_{CCO} + 0.125$	$V_{CCO} + 0.3$	—	—	—	—
DIFF SSTL18 II	-0.3	50% $V_{CCO} - 0.125$	50% $V_{CCO} + 0.125$	$V_{CCO} + 0.3$	—	—	—	—
SSTL15	-0.3	$V_{REF} - 0.1$	$V_{REF} + 0.1$	$V_{CCO} + 0.3$	$V_{TT} - 0.175$	$V_{TT} + 0.175$	14.3	14.3

Notes:

1. Tested according to relevant specifications.
2. Applies to both 1.5V and 1.8V HSTL.
3. Using drive strengths of 2, 4, 6, 8, 12, 16, or 24 mA.
4. Using drive strengths of 2, 4, 6, 8, 12, or 16 mA.
5. Supported drive strengths of 2, 4, 6, or 8 mA.
6. For detailed interface specific DC voltage levels, see [UG361](#): Virtex-6 FPGA SelectIO Resources User Guide.

GTX Transceiver Specifications

GTX Transceiver DC Characteristics

Table 13: Absolute Maximum Ratings for GTX Transceivers⁽¹⁾

Symbol	Description	Min	Max	Units
MGTAVCC	Analog supply voltage for the GTX transmitter and receiver circuits relative to GND	−0.5	1.1	V
MGTAVTT	Analog supply voltage for the GTX transmitter and receiver termination circuits relative to GND	−0.5	1.32	V
MGTAVTTRCAL	Analog supply voltage for the resistor calibration circuit of the GTX transceiver column	−0.5	1.32	V
V _{IN}	Receiver (RXP/RXN) and Transmitter (TXP/TXN) absolute input voltage	−0.5	1.32	V
V _{MGTREFCLK}	Reference clock absolute input voltage	−0.5	1.32	V

Notes:

- Stresses beyond those listed under Absolute Maximum Ratings might cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those listed under Operating Conditions is not implied. Exposure to Absolute Maximum Ratings conditions for extended periods of time might affect device reliability.

Table 14: Recommended Operating Conditions for GTX Transceivers⁽¹⁾⁽²⁾

Symbol	Description	Speed Grade	PLL Frequency	Min	Typ	Max	Units
MGTAVCC	Analog supply voltage for the GTX transmitter and receiver circuits relative to GND	-3, -2 ⁽³⁾	> 2.7 GHz	1.0	1.03	1.06	V
		-3, -2 ⁽³⁾	≤ 2.7 GHz	0.95	1.0	1.06	V
		-1	≤ 2.7 GHz	0.95	1.0	1.06	V
		-1L	≤ 2.7 GHz	0.95	1.0	1.05	V
MGTAVTT	Analog supply voltage for the GTX transmitter and receiver termination circuits relative to GND	All	—	1.14	1.2	1.26	V
MGTAVTTRCAL	Analog supply voltage for the resistor calibration circuit of the GTX transceiver column	All	—	1.14	1.2	1.26	V

Notes:

- Each voltage listed requires the filter circuit described in [UG366: Virtex-6 FPGA GTX Transceivers User Guide](#).
- Voltages are specified for the temperature range of T_j = −40°C to +100°C for all XC devices and T_j = −55°C to +125°C for the XQ devices.
- If a GTX Quad contains transceivers operating with a mixture of PLL frequencies above and below 2.7 GHz, the MGTAVCC voltage supply must be in the range of 1.0V to 1.06V.

Table 15: GTX Transceiver Supply Current (per Lane) ⁽¹⁾⁽²⁾

Symbol	Description	Typ	Max	Units
I _{MGTAVTT}	MGTAVTT supply current for one GTX transceiver	55.9	Note 2	mA
I _{MGTAVCC}	MGTAVCC supply current for one GTX transceiver	56.1		mA
MGTR _{REF}	Precision reference resistor for internal calibration termination	100.0 ± 1% tolerance		Ω

Notes:

- Typical values are specified at nominal voltage, 25°C, with a 3.125 Gb/s line rate.
- Values for currents of other transceiver configurations and conditions can be obtained by using the XPower Estimator (XPE) or XPower Analyzer (XPA) tools.

Table 23: GTX Transceiver Transmitter Switching Characteristics

Symbol	Description	Condition	Min	Typ	Max	Units
F _{GTXTX}	Serial data rate range		0.480	–	F _{GTXMAX}	Gb/s
T _{RTX}	TX Rise time	20%–80%	–	120	–	ps
T _{FTX}	TX Fall time	80%–20%	–	120	–	ps
T _{LLSKEW}	TX lane-to-lane skew ⁽¹⁾		–	–	350	ps
V _{TXOOBVDPP}	Electrical idle amplitude		–	–	15	mV
T _{TXOOBTRANSITION}	Electrical idle transition time		–	–	75	ns
TJ _{6.5}	Total Jitter ⁽²⁾⁽³⁾	6.5 Gb/s	–	–	0.33	UI
DJ _{6.5}	Deterministic Jitter ⁽²⁾⁽³⁾		–	–	0.17	UI
TJ _{5.0}	Total Jitter ⁽²⁾⁽³⁾	5.0 Gb/s	–	–	0.33	UI
DJ _{5.0}	Deterministic Jitter ⁽²⁾⁽³⁾		–	–	0.15	UI
TJ _{4.25}	Total Jitter ⁽²⁾⁽³⁾	4.25 Gb/s	–	–	0.33	UI
DJ _{4.25}	Deterministic Jitter ⁽²⁾⁽³⁾		–	–	0.14	UI
TJ _{3.75}	Total Jitter ⁽²⁾⁽³⁾	3.75 Gb/s	–	–	0.34	UI
DJ _{3.75}	Deterministic Jitter ⁽²⁾⁽³⁾		–	–	0.16	UI
TJ _{3.125}	Total Jitter ⁽²⁾⁽³⁾	3.125 Gb/s	–	–	0.2	UI
DJ _{3.125}	Deterministic Jitter ⁽²⁾⁽³⁾		–	–	0.1	UI
TJ _{3.125L}	Total Jitter ⁽²⁾⁽³⁾	3.125 Gb/s ⁽⁴⁾	–	–	0.35	UI
DJ _{3.125L}	Deterministic Jitter ⁽²⁾⁽³⁾		–	–	0.16	UI
TJ _{2.5}	Total Jitter ⁽²⁾⁽³⁾	2.5 Gb/s ⁽⁵⁾	–	–	0.20	UI
DJ _{2.5}	Deterministic Jitter ⁽²⁾⁽³⁾		–	–	0.08	UI
TJ _{1.25}	Total Jitter ⁽²⁾⁽³⁾	1.25 Gb/s ⁽⁶⁾	–	–	0.15	UI
DJ _{1.25}	Deterministic Jitter ⁽²⁾⁽³⁾		–	–	0.06	UI
TJ ₆₀₀	Total Jitter ⁽²⁾⁽³⁾	600 Mb/s	–	–	0.1	UI
DJ ₆₀₀	Deterministic Jitter ⁽²⁾⁽³⁾		–	–	0.03	UI
TJ ₄₈₀	Total Jitter ⁽²⁾⁽³⁾	480 Mb/s	–	–	0.1	UI
DJ ₄₈₀	Deterministic Jitter ⁽²⁾⁽³⁾		–	–	0.03	UI

Notes:

- Using same REFCLK input with TXENPMAPHASEALIGN enabled for up to 12 consecutive transmitters (three fully populated GTX Quads).
- Using PLL_DIVSEL_FB = 2, 20-bit internal data width. These values are NOT intended for protocol specific compliance determinations.
- All jitter values are based on a bit-error ratio of 1e⁻¹².
- PLL frequency at 1.5625 GHz and OUTDIV = 1.
- PLL frequency at 2.5 GHz and OUTDIV = 2.
- PLL frequency at 2.5 GHz and OUTDIV = 4.

Table 40: Analog-to-Digital Specifications (Cont'd)

Parameter	Symbol	Comments/Conditions	Min	Typ	Max	Units
Analog Inputs ⁽³⁾						
Dedicated Analog Inputs Input Voltage Range V _P - V _N		Unipolar Operation	0	–	1	Volts
		Bipolar Operation	–0.5	–	+0.5	
		Unipolar Common Mode Range (FS input)	0	–	+0.5	
		Bipolar Common Mode Range (FS input)	+0.5	–	+0.6	
		Bandwidth	–	20	–	MHz
Auxiliary Analog Inputs Input Voltage Range V _{AUXP[0]} /V _{AUXN[0]} to V _{AUXP[15]} /V _{AUXN[15]} T _j = –55°C to 125°C		Unipolar Operation	0	–	1	Volts
		Bipolar Operation	–0.5	–	+0.5	
		Unipolar Common Mode Range (FS input)	0	–	+0.5	
		Bipolar Common Mode Range (FS input)	+0.5	–	+0.6	
		Bandwidth	–	10	–	kHz
Input Leakage Current		A/D not converting, ADCCLK stopped	–	±1.0	–	µA
Input Capacitance			–	10	–	pF
On-chip Supply Monitor Error		V _{CCINT} and V _{CCAUX} with calibration enabled. External 1.25V reference T _j = –55°C to 125°C.	–	–	±1.0	% Reading
		V _{CCINT} and V _{CCAUX} with calibration enabled. Internal reference T _j = –40°C to 100°C. ⁽⁴⁾	–	±2	–	% Reading
On-chip Temperature Monitor Error		T _j = –55°C to +125°C with calibration enabled. External 1.25V reference.	–	–	±4	°C
		T _j = –40°C to +100°C with calibration enabled. Internal reference. ⁽⁴⁾	–	±5	–	°C
External Reference Inputs ⁽⁵⁾						
Positive Reference Input Voltage Range	V _{REFP}	Measured Relative to V _{REFN}	1.20	1.25	1.30	Volts
Negative Reference Input Voltage Range	V _{REFN}	Measured Relative to AGND	–50	0	100	mV
Input current	I _{REF}	ADCCLK = 5.2 MHz	–	–	100	µA
Power Requirements						
Analog Power Supply	AV _{DD}	Measured Relative to AV _{SS}	2.375	2.5	2.625	Volts
Analog Supply Current	AI _{DD}	ADCCLK = 5.2 MHz	–	–	12	mA

Notes:

- Offset errors are removed by enabling the System Monitor automatic gain calibration feature.
- See "System Monitor Timing" in [UG370: Virtex-6 FPGA System Monitor User Guide](#)
- See "Analog Inputs" in [UG370: Virtex-6 FPGA System Monitor User Guide](#) for a detailed description.
- These internal references are not specified over the junction temperature operating range for military (M) temperature devices.
- Any variation in the reference voltage from the nominal $V_{REFP} = 1.25\text{V}$ and $V_{REFN} = 0\text{V}$ will result in a deviation from the ideal transfer function. This also impacts the accuracy of the internal sensor measurements (i.e., temperature and power supply). However, for external ratiometric type applications allowing reference to vary by $\pm 4\%$ is permitted.

Performance Characteristics

This section provides the performance characteristics of some common functions and designs implemented in Virtex-6 devices. The numbers reported here are worst-case values; they have all been fully characterized. These values are subject to the same guidelines as the [Switching Characteristics, page 26](#).

Table 41: Interface Performances

Description	Speed Grade			
	-3	-2	-1	-1L
Networking Applications				
SDR LVDS transmitter (using OSERDES; DATA_WIDTH = 4 to 8)	710 Mb/s	710 Mb/s	650 Mb/s	585 Mb/s
DDR LVDS transmitter (using OSERDES; DATA_WIDTH = 4 to 10)	1.4 Gb/s	1.3 Gb/s	1.25 Gb/s	1.1 Gb/s
SDR LVDS receiver (SFI-4.1) ⁽¹⁾	710 Mb/s	710 Mb/s	650 Mb/s	585 Mb/s
DDR LVDS receiver (SPI-4.2) ⁽¹⁾	1.4 Gb/s	1.3 Gb/s	1.1 Gb/s	0.9 Gb/s
Maximum Physical Interface (PHY) Rate for Memory Interfaces⁽²⁾⁽³⁾⁽⁴⁾				
DDR2	800 Mb/s	800 Mb/s	800 Mb/s	606 Mb/s
DDR3	1066 Mb/s	1066 Mb/s	800 Mb/s	800 Mb/s
QDR II + SRAM	400 MHz	350 MHz	300 MHz	—
RLDRAM II	500 MHz	400 MHz	350 MHz	—

Notes:

1. LVDS receivers are typically bounded with certain applications where specific DPA algorithms dominate deterministic performance.
2. Verified on Xilinx memory characterization platforms designed according to the guidelines in UG: *Virtex-6 FPGA Memory Interface Solutions User Guide*.
3. Consult [DS186](#); *Virtex-6 FPGA Memory Interface Solutions Data Sheet* for performance and feature information on memory interface cores (controller plus PHY).
4. Memory Interface data rates have not been tested over the junction temperature operating range for military (M) temperature devices. Customers are responsible for specifying and testing their specific M temperature grade memory implementation.

Table 44: IOB Switching Characteristics for the Commercial (XC) Virtex-6 Devices (Cont'd)

I/O Standard	T _{IOPI}				T _{IOOP}				T _{IOTP}				Units
	Speed Grade				Speed Grade				Speed Grade				
	-3	-2	-1	-1L	-3	-2	-1	-1L	-3	-2	-1	-1L	
LVDCI_DV2_25	0.51	0.57	0.66	0.70	1.71	1.83	2.01	2.00	1.71	1.83	2.01	2.00	ns
LVDCI_DV2_18	0.55	0.61	0.71	0.73	1.69	1.81	2.00	1.98	1.69	1.81	2.00	1.98	ns
LVDCI_DV2_15	0.64	0.73	0.85	0.85	1.68	1.77	1.91	1.98	1.68	1.77	1.91	1.98	ns
LVPECL_25	0.85	0.94	1.09	1.08	1.38	1.49	1.65	1.64	1.38	1.49	1.65	1.64	ns
HSTL_I_12	0.81	0.91	1.06	1.06	1.48	1.60	1.78	1.74	1.48	1.60	1.78	1.74	ns
HSTL_I_DCI	0.81	0.91	1.06	1.06	1.40	1.50	1.66	1.64	1.40	1.50	1.66	1.64	ns
HSTL_II_DCI	0.81	0.91	1.06	1.06	1.37	1.49	1.68	1.66	1.37	1.49	1.68	1.66	ns
HSTL_II_T_DCI	0.81	0.91	1.06	1.06	1.40	1.50	1.66	1.64	1.40	1.50	1.66	1.64	ns
HSTL_III_DCI	0.81	0.91	1.06	1.06	1.34	1.45	1.62	1.61	1.34	1.45	1.62	1.61	ns
HSTL_I_DCI_18	0.81	0.91	1.06	1.06	1.42	1.53	1.68	1.66	1.42	1.53	1.68	1.66	ns
HSTL_II_DCI_18	0.81	0.91	1.06	1.06	1.36	1.46	1.62	1.59	1.36	1.46	1.62	1.59	ns
HSTL_II_T_DCI_18	0.81	0.91	1.06	1.06	1.42	1.53	1.68	1.66	1.42	1.53	1.68	1.66	ns
HSTL_III_DCI_18	0.81	0.91	1.06	1.06	1.43	1.54	1.69	1.67	1.43	1.54	1.69	1.67	ns
DIFF_HSTL_I_18	0.85	0.94	1.09	1.08	1.47	1.58	1.75	1.72	1.47	1.58	1.75	1.72	ns
DIFF_HSTL_I_DCI_18	0.85	0.94	1.09	1.08	1.42	1.53	1.68	1.66	1.42	1.53	1.68	1.66	ns
DIFF_HSTL_I	0.85	0.94	1.09	1.08	1.45	1.56	1.73	1.71	1.45	1.56	1.73	1.71	ns
DIFF_HSTL_I_DCI	0.85	0.94	1.09	1.08	1.40	1.50	1.66	1.64	1.40	1.50	1.66	1.64	ns
DIFF_HSTL_II_18	0.85	0.94	1.09	1.08	1.50	1.62	1.81	1.78	1.50	1.62	1.81	1.78	ns
DIFF_HSTL_II_DCI_18	0.85	0.94	1.09	1.08	1.36	1.46	1.62	1.59	1.36	1.46	1.62	1.59	ns
DIFF_HSTL_II_T_DCI_18	0.85	0.94	1.09	1.08	1.42	1.53	1.68	1.66	1.42	1.53	1.68	1.66	ns
DIFF_HSTL_II	0.85	0.94	1.09	1.08	1.44	1.56	1.74	1.72	1.44	1.56	1.74	1.72	ns
DIFF_HSTL_II_DCI	0.85	0.94	1.09	1.08	1.37	1.49	1.68	1.66	1.37	1.49	1.68	1.66	ns
SSTL2_I_DCI	0.81	0.91	1.06	1.06	1.42	1.53	1.70	1.68	1.42	1.53	1.70	1.68	ns
SSTL2_II_DCI	0.81	0.91	1.06	1.06	1.39	1.50	1.67	1.69	1.39	1.50	1.67	1.69	ns
SSTL2_II_T_DCI	0.81	0.91	1.06	1.06	1.42	1.53	1.70	1.68	1.42	1.53	1.70	1.68	ns
SSTL18_I	0.81	0.91	1.06	1.06	1.47	1.58	1.75	1.73	1.47	1.58	1.75	1.73	ns
SSTL18_II	0.81	0.91	1.06	1.06	1.39	1.50	1.67	1.66	1.39	1.50	1.67	1.66	ns
SSTL18_I_DCI	0.81	0.91	1.06	1.06	1.40	1.51	1.67	1.65	1.40	1.51	1.67	1.65	ns
SSTL18_II_DCI	0.81	0.91	1.06	1.06	1.36	1.47	1.63	1.62	1.36	1.47	1.63	1.62	ns
SSTL18_II_T_DCI	0.81	0.91	1.06	1.06	1.40	1.51	1.67	1.65	1.40	1.51	1.67	1.65	ns
SSTL15_T_DCI	0.81	0.91	1.06	1.06	1.41	1.52	1.68	1.66	1.41	1.52	1.68	1.66	ns
SSTL15_DCI	0.81	0.91	1.06	1.06	1.41	1.52	1.68	1.66	1.41	1.52	1.68	1.66	ns
DIFF_SSTL2_I	0.85	0.94	1.09	1.08	1.49	1.60	1.77	1.74	1.49	1.60	1.77	1.74	ns
DIFF_SSTL2_I_DCI	0.85	0.94	1.09	1.08	1.42	1.53	1.70	1.68	1.42	1.53	1.70	1.68	ns
DIFF_SSTL2_II	0.85	0.94	1.09	1.08	1.42	1.54	1.72	1.71	1.42	1.54	1.72	1.71	ns
DIFF_SSTL2_II_DCI	0.85	0.94	1.09	1.08	1.39	1.50	1.67	1.69	1.39	1.50	1.67	1.69	ns
DIFF_SSTL2_II_T_DCI	0.85	0.94	1.09	1.08	1.42	1.53	1.70	1.68	1.42	1.53	1.70	1.68	ns

Table 44: IOB Switching Characteristics for the Commercial (XC) Virtex-6 Devices (Cont'd)

I/O Standard	T _{IOPI}				T _{IOOP}				T _{IOTP}				Units
	Speed Grade				Speed Grade				Speed Grade				
	-3	-2	-1	-1L	-3	-2	-1	-1L	-3	-2	-1	-1L	
DIFF_SSTL18_I	0.85	0.94	1.09	1.08	1.47	1.58	1.75	1.73	1.47	1.58	1.75	1.73	ns
DIFF_SSTL18_I_DCI	0.85	0.94	1.09	1.08	1.40	1.51	1.67	1.65	1.40	1.51	1.67	1.65	ns
DIFF_SSTL18_II	0.85	0.94	1.09	1.08	1.39	1.50	1.67	1.66	1.39	1.50	1.67	1.66	ns
DIFF_SSTL18_II_DCI	0.85	0.94	1.09	1.08	1.36	1.47	1.63	1.62	1.36	1.47	1.63	1.62	ns
DIFF_SSTL18_II_T_DCI	0.85	0.94	1.09	1.08	1.40	1.51	1.67	1.65	1.40	1.51	1.67	1.65	ns
DIFF_SSTL15	0.81	0.91	1.06	1.06	1.42	1.54	1.71	1.69	1.42	1.54	1.71	1.69	ns
DIFF_SSTL15_DCI	0.81	0.91	1.06	1.06	1.41	1.52	1.68	1.66	1.41	1.52	1.68	1.66	ns
DIFF_SSTL15_T_DCI	0.81	0.91	1.06	1.06	1.41	1.52	1.68	1.66	1.41	1.52	1.68	1.66	ns

Table 45: IOB Switching Characteristics for the Defense-grade (XQ) Virtex-6 Devices

I/O Standard	T _{IOPI}			T _{IOOP}			T _{IOTP}			Units
	Speed Grade			Speed Grade			Speed Grade			
	-2	-1	-1L	-2	-1	-1L	-2	-1	-1L	
LVDS_25	0.94	1.09	1.08	1.54	2.16	1.62	1.54	2.16	1.62	ns
LVDSEXT_25	0.94	1.09	1.08	1.65	2.20	1.73	1.65	2.20	1.73	ns
HT_25	0.94	1.09	1.08	1.62	2.20	1.69	1.62	2.20	1.69	ns
BLVDS_25	0.94	1.09	1.08	1.50	3.18	1.65	1.50	3.18	1.65	ns
RSDS_25 (point to point)	0.94	1.09	1.08	1.54	2.22	1.62	1.54	2.22	1.62	ns
HSTL_I	0.91	1.06	1.06	1.56	2.44	1.71	1.56	2.44	1.71	ns
HSTL_II	0.91	1.06	1.06	1.56	2.21	1.72	1.56	2.21	1.72	ns
HSTL_III	0.91	1.06	1.06	1.54	2.50	1.69	1.54	2.50	1.69	ns
HSTL_I_18	0.91	1.06	1.06	1.58	2.43	1.72	1.58	2.43	1.72	ns
HSTL_II_18	0.91	1.06	1.06	1.62	2.30	1.78	1.62	2.30	1.78	ns
HSTL_III_18	0.91	1.06	1.06	1.54	2.49	1.69	1.54	2.49	1.69	ns
SSTL2_I	0.91	1.06	1.06	1.60	2.50	1.74	1.60	2.50	1.74	ns
SSTL2_II	0.91	1.06	1.06	1.54	2.49	1.71	1.54	2.49	1.71	ns
SSTL15	0.91	1.06	1.06	1.54	2.07	1.69	1.54	2.07	1.69	ns
LVC MOS25, Slow, 2 mA	0.57	0.66	0.70	5.46	6.01	5.63	5.46	6.01	5.63	ns
LVC MOS25, Slow, 4 mA	0.57	0.66	0.70	3.49	3.79	3.65	3.49	3.79	3.65	ns
LVC MOS25, Slow, 6 mA	0.57	0.66	0.70	2.81	3.08	2.95	2.81	3.08	2.95	ns
LVC MOS25, Slow, 8 mA	0.57	0.66	0.70	2.41	2.72	2.59	2.41	2.72	2.59	ns
LVC MOS25, Slow, 12 mA	0.57	0.66	0.70	1.95	2.23	2.10	1.95	2.23	2.10	ns
LVC MOS25, Slow, 16 mA	0.57	0.66	0.70	2.05	2.29	2.21	2.05	2.29	2.21	ns
LVC MOS25, Slow, 24 mA	0.57	0.66	0.70	1.82	2.24	1.98	1.82	2.24	1.98	ns
LVC MOS25, Fast, 2 mA	0.57	0.66	0.70	5.49	6.04	5.62	5.49	6.04	5.62	ns
LVC MOS25, Fast, 4 mA	0.57	0.66	0.70	3.50	3.82	3.65	3.50	3.82	3.65	ns
LVC MOS25, Fast, 6 mA	0.57	0.66	0.70	2.73	2.99	2.88	2.73	2.99	2.88	ns
LVC MOS25, Fast, 8 mA	0.57	0.66	0.70	2.33	2.65	2.53	2.33	2.65	2.53	ns
LVC MOS25, Fast, 12 mA	0.57	0.66	0.70	1.88	2.08	2.03	1.88	2.08	2.03	ns

Table 45: IOB Switching Characteristics for the Defense-grade (XQ) Virtex-6 Devices (Cont'd)

I/O Standard	T _{IOPI}			T _{IOOP}			T _{IOTP}			Units
	Speed Grade			Speed Grade			Speed Grade			
	-2	-1	-1L	-2	-1	-1L	-2	-1	-1L	
LVC MOS25, Fast, 16 mA	0.57	0.66	0.70	1.92	2.15	2.08	1.92	2.15	2.08	ns
LVC MOS25, Fast, 24 mA	0.57	0.66	0.70	1.79	2.15	1.96	1.79	2.15	1.96	ns
LVC MOS18, Slow, 2 mA	0.61	0.71	0.73	4.47	4.87	4.30	4.47	4.87	4.30	ns
LVC MOS18, Slow, 4 mA	0.61	0.71	0.73	2.96	3.21	2.94	2.96	3.21	2.94	ns
LVC MOS18, Slow, 6 mA	0.61	0.71	0.73	2.43	2.64	2.47	2.43	2.64	2.47	ns
LVC MOS18, Slow, 8 mA	0.61	0.71	0.73	2.11	2.41	2.24	2.11	2.41	2.24	ns
LVC MOS18, Slow, 12 mA	0.61	0.71	0.73	1.99	2.30	2.10	1.99	2.30	2.10	ns
LVC MOS18, Slow, 16 mA	0.61	0.71	0.73	1.95	2.30	2.04	1.95	2.30	2.04	ns
LVC MOS18, Fast, 2 mA	0.61	0.71	0.73	4.23	4.57	4.08	4.23	4.57	4.08	ns
LVC MOS18, Fast, 4 mA	0.61	0.71	0.73	2.76	2.97	2.74	2.76	2.97	2.74	ns
LVC MOS18, Fast, 6 mA	0.61	0.71	0.73	2.28	2.46	2.32	2.28	2.46	2.32	ns
LVC MOS18, Fast, 8 mA	0.61	0.71	0.73	1.99	2.34	2.14	1.99	2.34	2.14	ns
LVC MOS18, Fast, 12 mA	0.61	0.71	0.73	1.80	2.19	1.88	1.80	2.19	1.88	ns
LVC MOS18, Fast, 16 mA	0.61	0.71	0.73	1.74	2.18	1.88	1.74	2.18	1.88	ns
LVC MOS15, Slow, 2 mA	0.73	0.85	0.85	3.77	4.29	3.91	3.77	4.29	3.91	ns
LVC MOS15, Slow, 4 mA	0.73	0.85	0.85	2.79	3.10	2.93	2.79	3.10	2.93	ns
LVC MOS15, Slow, 6 mA	0.73	0.85	0.85	2.32	2.68	2.50	2.32	2.68	2.50	ns
LVC MOS15, Slow, 8 mA	0.73	0.85	0.85	1.98	2.29	2.24	1.98	2.29	2.24	ns
LVC MOS15, Slow, 12 mA	0.73	0.85	0.85	1.91	2.23	2.07	1.91	2.23	2.07	ns
LVC MOS15, Slow, 16 mA	0.73	0.85	0.85	1.83	2.23	1.98	1.83	2.23	1.98	ns
LVC MOS15, Fast, 2 mA	0.73	0.85	0.85	3.77	4.28	3.91	3.77	4.28	3.91	ns
LVC MOS15, Fast, 4 mA	0.73	0.85	0.85	2.53	2.78	2.66	2.53	2.78	2.66	ns
LVC MOS15, Fast, 6 mA	0.73	0.85	0.85	2.05	2.42	2.16	2.05	2.42	2.16	ns
LVC MOS15, Fast, 8 mA	0.73	0.85	0.85	1.90	2.20	2.04	1.90	2.20	2.04	ns
LVC MOS15, Fast, 12 mA	0.73	0.85	0.85	1.77	2.11	1.90	1.77	2.11	1.90	ns
LVC MOS15, Fast, 16 mA	0.73	0.85	0.85	1.76	2.11	1.92	1.76	2.11	1.92	ns
LVC MOS12, Slow, 2 mA	0.81	0.93	0.95	3.39	3.75	3.54	3.39	3.75	3.54	ns
LVC MOS12, Slow, 4 mA	0.81	0.93	0.95	2.63	2.93	2.79	2.63	2.93	2.79	ns
LVC MOS12, Slow, 6 mA	0.81	0.93	0.95	2.11	2.67	2.26	2.11	2.67	2.26	ns
LVC MOS12, Slow, 8 mA	0.81	0.93	0.95	2.02	2.25	2.17	2.02	2.25	2.17	ns
LVC MOS12, Fast, 2 mA	0.81	0.93	0.95	2.98	3.39	3.11	2.98	3.39	3.11	ns
LVC MOS12, Fast, 4 mA	0.81	0.93	0.95	2.16	2.70	2.31	2.16	2.70	2.31	ns
LVC MOS12, Fast, 6 mA	0.81	0.93	0.95	1.89	2.34	2.05	1.89	2.34	2.05	ns
LVC MOS12, Fast, 8 mA	0.81	0.93	0.95	1.82	2.10	1.98	1.82	2.10	1.98	ns
LVDCI_25	0.57	0.70	0.70	2.14	2.82	2.26	2.14	2.82	2.26	ns
LVDCI_18	0.61	0.71	0.73	2.23	2.78	2.38	2.23	2.78	2.38	ns
LVDCI_15	0.73	0.85	0.85	2.01	2.75	2.18	2.01	2.75	2.18	ns
LVDCI_DV2_25	0.57	0.70	0.70	1.83	2.37	2.00	1.83	2.37	2.00	ns

Table 45: IOB Switching Characteristics for the Defense-grade (XQ) Virtex-6 Devices (Cont'd)

I/O Standard	T _{IOPI}			T _{IOOP}			T _{IOTP}			Units
	Speed Grade			Speed Grade			Speed Grade			
	-2	-1	-1L	-2	-1	-1L	-2	-1	-1L	
LVDCI_DV2_18	0.61	0.72	0.73	1.81	2.36	1.98	1.81	2.36	1.98	ns
LVDCI_DV2_15	0.73	0.85	0.85	1.77	2.30	1.98	1.77	2.30	1.98	ns
LVPECL_25	0.94	1.09	1.08	1.49	2.68	1.64	1.49	2.68	1.64	ns
HSTL_I_12	0.91	1.06	1.06	1.60	2.48	1.74	1.60	2.48	1.74	ns
HSTL_I_DCI	0.91	1.06	1.06	1.50	2.43	1.64	1.50	2.43	1.64	ns
HSTL_II_DCI	0.91	1.06	1.06	1.49	2.39	1.66	1.49	2.39	1.66	ns
HSTL_II_T_DCI	0.91	1.06	1.06	1.50	2.43	1.64	1.50	2.43	1.64	ns
HSTL_III_DCI	0.91	1.06	1.06	1.45	2.48	1.61	1.45	2.48	1.61	ns
HSTL_I_DCI_18	0.91	1.06	1.06	1.53	2.44	1.66	1.53	2.44	1.66	ns
HSTL_II_DCI_18	0.91	1.06	1.06	1.46	2.41	1.59	1.46	2.41	1.59	ns
HSTL_II_T_DCI_18	0.91	1.06	1.06	1.53	2.43	1.66	1.53	2.43	1.66	ns
HSTL_III_DCI_18	0.91	1.06	1.06	1.54	2.50	1.67	1.54	2.50	1.67	ns
DIFF_HSTL_I_18	0.94	1.09	1.08	1.58	2.30	1.72	1.58	2.30	1.72	ns
DIFF_HSTL_I_DCI_18	0.94	1.09	1.08	1.53	2.21	1.66	1.53	2.21	1.66	ns
DIFF_HSTL_I	0.94	1.09	1.08	1.56	2.28	1.71	1.56	2.28	1.71	ns
DIFF_HSTL_I_DCI	0.94	1.09	1.08	1.50	2.28	1.64	1.50	2.28	1.64	ns
DIFF_HSTL_II_18	0.94	1.09	1.08	1.62	2.33	1.78	1.62	2.33	1.78	ns
DIFF_HSTL_II_DCI_18	0.94	1.09	1.08	1.46	2.18	1.59	1.46	2.18	1.59	ns
DIFF_HSTL_II_T_DCI_18	0.94	1.09	1.08	1.53	2.22	1.66	1.53	2.22	1.66	ns
DIFF_HSTL_II	0.94	1.09	1.08	1.56	2.29	1.72	1.56	2.29	1.72	ns
DIFF_HSTL_II_DCI	0.94	1.09	1.08	1.49	2.26	1.66	1.49	2.26	1.66	ns
SSTL2_I_DCI	0.91	1.06	1.06	1.53	2.51	1.68	1.53	2.51	1.68	ns
SSTL2_II_DCI	0.91	1.06	1.06	1.50	2.50	1.69	1.50	2.50	1.69	ns
SSTL2_II_T_DCI	0.91	1.06	1.06	1.53	2.52	1.68	1.53	2.52	1.68	ns
SSTL18_I	0.91	1.06	1.06	1.58	2.48	1.73	1.58	2.48	1.73	ns
SSTL18_II	0.91	1.06	1.06	1.50	2.46	1.66	1.50	2.46	1.66	ns
SSTL18_I_DCI	0.91	1.06	1.06	1.51	2.49	1.65	1.51	2.49	1.65	ns
SSTL18_II_DCI	0.91	1.06	1.06	1.47	2.41	1.62	1.47	2.41	1.62	ns
SSTL18_II_T_DCI	0.91	1.06	1.06	1.51	2.49	1.65	1.51	2.49	1.65	ns
SSTL15_T_DCI	0.91	1.06	1.06	1.52	2.48	1.66	1.52	2.48	1.66	ns
SSTL15_DCI	0.91	1.06	1.06	1.52	2.48	1.66	1.52	2.48	1.66	ns
DIFF_SSTL2_I	0.94	1.09	1.08	1.60	2.34	1.74	1.60	2.34	1.74	ns
DIFF_SSTL2_I_DCI	0.94	1.09	1.08	1.53	2.25	1.68	1.53	2.25	1.68	ns
DIFF_SSTL2_II	0.94	1.09	1.08	1.54	2.29	1.71	1.54	2.29	1.71	ns
DIFF_SSTL2_II_DCI	0.94	1.09	1.08	1.50	2.23	1.69	1.50	2.23	1.69	ns
DIFF_SSTL2_II_T_DCI	0.94	1.09	1.08	1.53	2.26	1.68	1.53	2.26	1.68	ns
DIFF_SSTL18_I	0.94	1.09	1.08	1.58	2.22	1.73	1.58	2.22	1.73	ns
DIFF_SSTL18_I_DCI	0.94	1.09	1.08	1.51	2.30	1.65	1.51	2.30	1.65	ns

I/O Standard Adjustment Measurement Methodology

Input Delay Measurements

Table 47 shows the test setup parameters used for measuring input delay.

Table 47: Input Delay Measurement Methodology

Description	I/O Standard Attribute	$V_L^{(1)(2)}$	$V_H^{(1)(2)}$	$V_{MEAS}^{(1)(4)(5)}$	$V_{REF}^{(1)(3)(5)}$
LVC MOS, 2.5V	LVC MOS25	0	2.5	1.25	—
LVC MOS, 1.8V	LVC MOS18	0	1.8	0.9	—
LVC MOS, 1.5V	LVC MOS15	0	1.5	0.75	—
HSTL (High-Speed Transceiver Logic), Class I & II	HSTL_I, HSTL_II	$V_{REF} - 0.5$	$V_{REF} + 0.5$	V_{REF}	0.75
HSTL, Class III	HSTL_III	$V_{REF} - 0.5$	$V_{REF} + 0.5$	V_{REF}	0.90
HSTL, Class I & II, 1.8V	HSTL_I_18, HSTL_II_18	$V_{REF} - 0.5$	$V_{REF} + 0.5$	V_{REF}	0.90
HSTL, Class III 1.8V	HSTL_III_18	$V_{REF} - 0.5$	$V_{REF} + 0.5$	V_{REF}	1.08
SSTL (Stub Terminated Transceiver Logic), Class I & II, 3.3V	SSTL3_I, SSTL3_II	$V_{REF} - 1.00$	$V_{REF} + 1.00$	V_{REF}	1.5
SSTL, Class I & II, 2.5V	SSTL2_I, SSTL2_II	$V_{REF} - 0.75$	$V_{REF} + 0.75$	V_{REF}	1.25
SSTL, Class I & II, 1.8V	SSTL18_I, SSTL18_II	$V_{REF} - 0.5$	$V_{REF} + 0.5$	V_{REF}	0.90
LVDS (Low-Voltage Differential Signaling), 2.5V	LVDS_25	$1.2 - 0.125$	$1.2 + 0.125$	$0^{(6)}$	—
LVDS EXT (LVDS Extended Mode), 2.5V	LVDS EXT_25	$1.2 - 0.125$	$1.2 + 0.125$	$0^{(6)}$	—
HT (HyperTransport), 2.5V	LDT_25	$0.6 - 0.125$	$0.6 + 0.125$	$0^{(6)}$	—

Notes:

1. The input delay measurement methodology parameters for LVDCI are the same for LVC MOS standards of the same voltage. Input delay measurement methodology parameters for HSLVDCI are the same as for HSTL_II standards of the same voltage. Parameters for all other DCI standards are the same for the corresponding non-DCI standards.
2. Input waveform switches between V_L and V_H .
3. Measurements are made at typical, minimum, and maximum V_{REF} values. Reported delays reflect worst case of these measurements. V_{REF} values listed are typical.
4. Input voltage level from which measurement starts.
5. This is an input voltage reference that bears no relation to the V_{REF} / V_{MEAS} parameters found in IBIS models and/or noted in Figure 6.
6. The value given is the differential input voltage.

Output Delay Measurements

Output delays are measured using a Tektronix P6245 TDS500/600 probe (< 1 pF) across approximately 4" of FR4 microstrip trace. Standard termination was used for all testing. The propagation delay of the 4" trace is characterized separately and subtracted from the final measurement, and is therefore not included in the generalized test setups shown in Figure 6 and Figure 7.

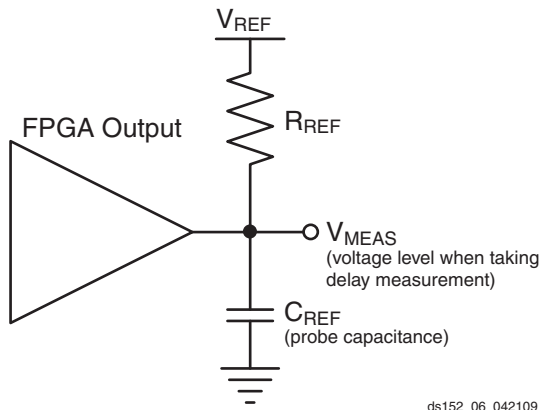
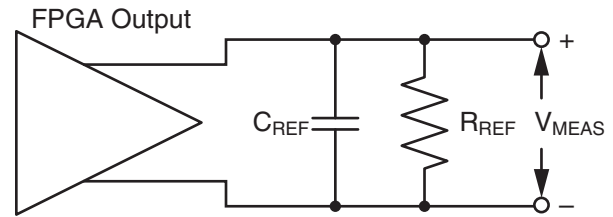


Figure 6: Single Ended Test Setup



ds152_07_042109

Figure 7: Differential Test Setup

Measurements and test conditions are reflected in the IBIS models except where the IBIS format precludes it. Parameters V_{REF} , R_{REF} , C_{REF} , and V_{MEAS} fully describe the test conditions for each I/O standard. The most accurate prediction of propagation delay in any given application can be obtained through IBIS simulation, using the following method:

1. Simulate the output driver of choice into the generalized test setup, using values from Table 48.
2. Record the time to V_{MEAS} .
3. Simulate the output driver of choice into the actual PCB trace and load, using the appropriate IBIS model or capacitance value to represent the load.
4. Record the time to V_{MEAS} .
5. Compare the results of steps 2 and 4. The increase or decrease in delay yields the actual propagation delay of the PCB trace.

Table 48: Output Delay Measurement Methodology

Description	I/O Standard Attribute	R_{REF} (Ω)	$C_{REF}^{(1)}$ (pF)	V_{MEAS} (V)	V_{REF} (V)
LVC MOS, 2.5V	LVC MOS25	1M	0	1.25	0
LVC MOS, 1.8V	LVC MOS18	1M	0	0.9	0
LVC MOS, 1.5V	LVC MOS15	1M	0	0.75	0
LVC MOS, 1.2V	LVC MOS12	1M	0	0.75	0
HSTL (High-Speed Transceiver Logic), Class I	HSTL_I	50	0	V_{REF}	0.75
HSTL, Class II	HSTL_II	25	0	V_{REF}	0.75
HSTL, Class III	HSTL_III	50	0	0.9	1.5
HSTL, Class I, 1.8V	HSTL_I_18	50	0	V_{REF}	0.9
HSTL, Class II, 1.8V	HSTL_II_18	25	0	V_{REF}	0.9
HSTL, Class III, 1.8V	HSTL_III_18	50	0	1.1	1.8
SSTL (Stub Series Terminated Logic), Class I, 1.8V	SSTL18_I	50	0	V_{REF}	0.9
SSTL, Class II, 1.8V	SSTL18_II	25	0	V_{REF}	0.9
SSTL, Class I, 2.5V	SSTL2_I	50	0	V_{REF}	1.25
SSTL, Class II, 2.5V	SSTL2_II	25	0	V_{REF}	1.25
LVDS (Low-Voltage Differential Signaling), 2.5V	LVDS_25	100	0	0 ⁽²⁾	1.2
LVDS EXT (LVDS Extended Mode), 2.5V	LVDS_25	100	0	0 ⁽²⁾	1.2
BLVDS (Bus LVDS), 2.5V	BLVDS_25	100	0	0 ⁽²⁾	0

Table 48: Output Delay Measurement Methodology (Cont'd)

Description	I/O Standard Attribute	R _{REF} (Ω)	C _{REF} ⁽¹⁾ (pF)	V _{MEAS} (V)	V _{REF} (V)
HT (HyperTransport), 2.5V	LDT_25	100	0	0 ⁽²⁾	0.6
LVPECL (Low-Voltage Positive Emitter-Coupled Logic), 2.5V	LVPECL_25	100	0	0 ⁽²⁾	0
LVDCI/HSLVDCI, 2.5V	LVDCI_25, HSLVDCI_25	1M	0	1.25	0
LVDCI/HSLVDCI, 1.8V	LVDCI_18, HSLVDCI_18	1M	0	0.9	0
LVDCI/HSLVDCI, 1.5V	LVDCI_15, HSLVDCI_15	1M	0	0.75	0
HSTL (High-Speed Transceiver Logic), Class I & II, with DCI	HSTL_I_DCI, HSTL_II_DCI	50	0	V _{REF}	0.75
HSTL, Class III, with DCI	HSTL_III_DCI	50	0	0.9	1.5
HSTL, Class I & II, 1.8V, with DCI	HSTL_I_DCI_18, HSTL_II_DCI_18	50	0	V _{REF}	0.9
HSTL, Class III, 1.8V, with DCI	HSTL_III_DCI_18	50	0	1.1	1.8
SSTL (Stub Series Termination Logic), Class I & II, 1.8V, with DCI	SSTL18_I_DCI, SSTL18_II_DCI	50	0	V _{REF}	0.9
SSTL, Class I & II, 2.5V, with DCI	SSTL2_I_DCI, SSTL2_II_DCI	50	0	V _{REF}	1.25

Notes:

1. C_{REF} is the capacitance of the probe, nominally 0 pF.
2. The value given is the differential output voltage.

Input/Output Logic Switching Characteristics

Table 49: ILOGIC Switching Characteristics

Symbol	Description	Speed Grade				Units
		-3	-2	-1	-1L	
Setup/Hold						
T _{ICE1CK} /T _{ICKCE1}	CE1 pin Setup/Hold with respect to CLK	0.21/ 0.03	0.25/ 0.04	0.27/ 0.04	0.31/ 0.05	ns
T _{ISRCK} /T _{ICKSR}	SR pin Setup/Hold with respect to CLK	0.66/ −0.08	0.78/ −0.08	0.96/ −0.08	1.09/ −0.11	ns
T _{IDOCK} /T _{IOCKD}	D pin Setup/Hold with respect to CLK without Delay	0.07/ 0.41	0.08/ 0.46	0.10/ 0.54	0.11/ 0.64	ns
T _{IDOCKD} /T _{IOCKDD}	DDLY pin Setup/Hold with respect to CLK (using IODELAY)	0.10/ 0.32	0.12/ 0.36	0.14/ 0.42	0.16/ 0.50	ns
Combinatorial						
T _{IDI}	D pin to O pin propagation delay, no Delay	0.15	0.17	0.20	0.23	ns
T _{IDID}	DDLY pin to O pin propagation delay (using IODELAY)	0.19	0.22	0.25	0.28	ns
Sequential Delays						
T _{IDLO}	D pin to Q1 pin using flip-flop as a latch without Delay	0.48	0.54	0.64	0.73	ns
T _{IDLOD}	DDLY pin to Q1 pin using flip-flop as a latch (using IODELAY)	0.52	0.58	0.68	0.78	ns
T _{ICKQ}	CLK to Q outputs	0.54	0.61	0.70	0.93	ns
T _{RQ_ILOGIC}	SR pin to OQ/TQ out	0.85	0.97	1.15	1.32	ns
T _{GSRQ_ILOGIC}	Global Set/Reset to Q outputs	7.60	7.60	10.51	10.51	ns
Set/Reset						
T _{RPW_ILOGIC}	Minimum Pulse Width, SR inputs	0.78	0.95	1.20	1.30	ns, Min

Table 50: OLOGIC Switching Characteristics

Symbol	Description	Speed Grade					Units
		-3	-2	-1 (XC)	-1 (XQ)	-1L	
Setup/Hold							
T _{ODCK} /T _{OCKD}	D1/D2 pins Setup/Hold with respect to CLK	0.45/ −0.08	0.50/ −0.08	0.54/ −0.08	0.54/ −0.08	0.69/ −0.11	ns
T _{OOCECK} /T _{OCKOCE}	OCE pin Setup/Hold with respect to CLK	0.17/ −0.03	0.20/ −0.03	0.22/ −0.03	0.27/ −0.05	0.27/ −0.04	ns
T _{OSRCK} /T _{OCKSR}	SR pin Setup/Hold with respect to CLK	0.59/ −0.24	0.62/ −0.24	0.54/ −0.08	0.54/ −0.08	0.79/ −0.35	ns
T _{OTCK} /T _{OCKT}	T1/T2 pins Setup/Hold with respect to CLK	0.44/ −0.07	0.51/ −0.07	0.56/ −0.07	0.60/ −0.10	0.68/ −0.13	ns
T _{OTCECK} /T _{OCKTCE}	TCE pin Setup/Hold with respect to CLK	0.15/ −0.04	0.19/ −0.04	0.21/ −0.04	0.27/ −0.05	0.29/ −0.05	ns
Combinatorial							
T _{DOQ}	D1 to OQ out or T1 to TQ out	0.78	0.87	1.01	1.01	1.15	ns
Sequential Delays							
T _{OCKQ}	CLK to OQ/TQ out	0.54	0.61	0.71	0.71	0.80	ns
T _{RQ}	SR pin to OQ/TQ out	0.80	0.90	1.05	1.05	1.19	ns
T _{GSRQ}	Global Set/Reset to Q outputs	7.60	7.60	10.51	10.51	10.51	ns
Set/Reset							
T _{RPW}	Minimum Pulse Width, SR inputs	0.78	0.95	1.20	1.20	1.30	ns, Min

Output Serializer/Deserializer Switching Characteristics

Table 52: OSERDES Switching Characteristics

Symbol	Description	Speed Grade					Units
		-3	-2	-1 (XC)	-1 (XQ)	-1L	
Setup/Hold							
T _{OSDCK_D} /T _{OSCKD_D}	D input Setup/Hold with respect to CLKDIV	0.23/ −0.10	0.28/ −0.10	0.31/ −0.10	0.35/ −0.10	0.36/ −0.15	ns
T _{OSDCK_T} /T _{OSCKD_T} ⁽¹⁾	T input Setup/Hold with respect to CLK	0.44/ −0.10	0.51/ −0.09	0.56/ −0.08	0.60/ −0.08	0.68/ −0.15	ns
T _{OSDCK_T2} /T _{OSCKD_T2} ⁽¹⁾	T input Setup/Hold with respect to CLKDIV	0.25/ −0.10	0.27/ −0.09	0.31/ −0.08	0.31/ −0.08	0.47/ −0.15	ns
T _{OSCCK_OCE} /T _{OSCKC_OCE}	OCE input Setup/Hold with respect to CLK	0.17/ −0.03	0.20/ −0.03	0.22/ −0.03	0.27/ −0.03	0.27/ −0.04	ns
T _{OSCCK_S}	SR (Reset) input Setup with respect to CLKDIV	0.07	0.07	0.07	0.07	0.08	ns
T _{OSCCK_TCE} /T _{OSCKC_TCE}	TCE input Setup/Hold with respect to CLK	0.15/ −0.04	0.19/ −0.04	0.21/ −0.04	0.27/ −0.04	0.29/ −0.05	ns
Sequential Delays							
T _{OSCKO_OQ}	Clock to out from CLK to OQ	0.63	0.71	0.82	0.82	0.93	ns
T _{OSCKO_TQ}	Clock to out from CLK to TQ	0.63	0.71	0.82	0.82	0.93	ns
Combinatorial							
T _{OSDO_TTQ}	T input to TQ Out	0.76	0.84	0.97	0.97	1.11	ns

Notes:

- T_{OSDCK_T2} and T_{OSCKD_T2} are reported as T_{OSDCK_T}/T_{OSCKD_T} in TRACE report.

Table 54: CLB Switching Characteristics (Cont'd)

Symbol	Description	Speed Grade				Units
		-3	-2	-1	-1L	
T _{ITO}	An – Dn inputs to A – D Q outputs	0.59	0.67	0.79	0.85	ns, Max
T _{AXA}	AX inputs to AMUX output	0.31	0.35	0.42	0.44	ns, Max
T _{AXB}	AX inputs to BMUX output	0.35	0.39	0.47	0.50	ns, Max
T _{AXC}	AX inputs to CMUX output	0.39	0.44	0.52	0.56	ns, Max
T _{AXD}	AX inputs to DMUX output	0.42	0.47	0.55	0.60	ns, Max
T _{BXB}	BX inputs to BMUX output	0.30	0.34	0.39	0.44	ns, Max
T _{BXD}	BX inputs to DMUX output	0.38	0.43	0.50	0.55	ns, Max
T _{CXC}	CX inputs to CMUX output	0.26	0.29	0.34	0.37	ns, Max
T _{CXD}	CX inputs to DMUX output	0.30	0.34	0.40	0.44	ns, Max
T _{DXD}	DX inputs to DMUX output	0.30	0.33	0.38	0.43	ns, Max
T _{OPCYA}	An input to COUT output	0.32	0.36	0.41	0.47	ns, Max
T _{OPCYB}	Bn input to COUT output	0.32	0.36	0.41	0.47	ns, Max
T _{OPCYC}	Cn input to COUT output	0.27	0.30	0.34	0.40	ns, Max
T _{OPCYD}	Dn input to COUT output	0.25	0.28	0.32	0.37	ns, Max
T _{AXCY}	AX input to COUT output	0.25	0.28	0.33	0.36	ns, Max
T _{BXCY}	BX input to COUT output	0.22	0.24	0.28	0.31	ns, Max
T _{CXCY}	CX input to COUT output	0.15	0.17	0.20	0.22	ns, Max
T _{DXCY}	DX input to COUT output	0.14	0.16	0.19	0.21	ns, Max
T _{BYP}	CIN input to COUT output	0.06	0.07	0.08	0.09	ns, Max
T _{CINA}	CIN input to AMUX output	0.21	0.24	0.28	0.30	ns, Max
T _{CINB}	CIN input to BMUX output	0.23	0.25	0.29	0.31	ns, Max
T _{CINC}	CIN input to CMUX output	0.23	0.26	0.30	0.33	ns, Max
T _{CIND}	CIN input to DMUX output	0.25	0.29	0.33	0.36	ns, Max
Sequential Delays						
T _{CKO}	Clock to AQ – DQ outputs	0.29	0.33	0.39	0.44	ns, Max
T _{SHCKO}	Clock to AMUX – DMUX outputs	0.36	0.40	0.47	0.53	ns, Max
Setup and Hold Times of CLB Flip-Flops Before/After Clock CLK						
T _{DICK} /T _{CKDI}	A – D input to CLK on A – D Flip Flops	0.30/0.17	0.36/0.18	0.43/0.20	0.44/0.25	ns, Min
T _{CECK_CLB} / T _{CKCE_CLB}	CE input to CLK on A – D Flip Flops	0.20/0.00	0.25/0.00	0.32/0.00	0.32/0.01	ns, Min
T _{SRCK} /T _{CKSR}	SR input to CLK on A – D Flip Flops	0.39/–0.07	0.44/–0.07	0.52/–0.07	0.58/–0.08	ns, Min
T _{CINCK} /T _{CKCIN}	CIN input to CLK on A – D Flip Flops	0.16/0.12	0.19/0.14	0.24/0.16	0.23/0.22	ns, Min
Set/Reset						
T _{SRMIN}	SR input minimum pulse width	0.90	0.90	0.97	0.80	ns, Min
T _{RQ}	Delay from SR input to AQ – DQ flip-flops	0.52	0.58	0.68	0.77	ns, Max
T _{CEO}	Delay from CE input to AQ – DQ flip-flops	0.41	0.48	0.59	0.61	ns, Max
F _{TOG}	Toggle frequency (for export control)	1412.00	1286.40	1098.00	1098.00	MHz

Notes:

1. A Zero “0” Hold Time listing indicates no hold time or a negative hold time. Negative values can not be guaranteed “best-case”, but if a “0” is listed, there is no positive hold time.
2. These items are of interest for Carry Chain applications.

Clock Switching Characteristics

The parameters in this section provide the necessary values for calculating timing budgets for Virtex-6 FPGA clock transmitter and receiver data-valid windows.

Table 71: Duty Cycle Distortion and Clock-Tree Skew

Symbol	Description	Device	Speed Grade				Units
			-3	-2	-1	-1L	
T_{DCD_CLK}	Global Clock Tree Duty Cycle Distortion ⁽¹⁾	All	0.12	0.12	0.12	0.12	ns
T_{CKSKEW}	Global Clock Tree Skew ⁽²⁾	XC6VLX75T	0.15	0.16	0.18	0.17	ns
		XC6VLX130T	0.25	0.26	0.29	0.28	ns
		XC6VLX195T	0.26	0.27	0.31	0.30	ns
		XC6VLX240T	0.26	0.27	0.31	0.30	ns
		XC6VLX365T	0.28	0.29	0.31	0.31	ns
		XC6VLX550T	N/A	0.50	0.54	0.54	ns
		XC6VLX760	N/A	0.51	0.56	0.56	ns
		XC6VSX315T	0.27	0.28	0.32	0.30	ns
		XC6VSX475T	N/A	0.39	0.44	0.42	ns
		XC6VHX250T	0.25	0.26	0.29	N/A	ns
		XC6VHX255T	0.35	0.37	0.41	N/A	ns
		XC6VHX380T	0.45	0.47	0.52	N/A	ns
		XC6VHX565T	N/A	0.46	0.51	N/A	ns
		XQ6VLX130T	N/A	0.26	0.29	0.28	ns
		XQ6VLX240T	N/A	0.27	0.31	0.30	ns
		XQ6VLX550T	N/A	N/A	0.54	0.54	ns
		XQ6VSX315T	N/A	0.28	0.32	0.30	ns
		XQ6VSX475T	N/A	N/A	0.44	0.42	ns
T_{DCD_BUFIO}	I/O clock tree duty cycle distortion	All	0.08	0.08	0.08	0.08	ns
T_{BUFIO_SKEW}	I/O clock tree skew across one clock region	All	0.03	0.03	0.03	0.02	ns
T_{BUFIO_SKEW2}	I/O clock tree skew across three clock regions	All	0.10	0.12	0.23	0.12	ns
T_{DCD_BUFR}	Regional clock tree duty cycle distortion	All	0.15	0.15	0.15	0.15	ns

Notes:

- These parameters represent the worst-case duty cycle distortion observable at the pins of the device using LVDS output buffers. For cases where other I/O standards are used, IBIS can be used to calculate any additional duty cycle distortion that might be caused by asymmetrical rise/fall times.
- The T_{CKSKEW} value represents the worst-case clock-tree skew observable between sequential I/O elements. Significantly less clock-tree skew exists for I/O registers that are close to each other and fed by the same or adjacent clock-tree branches. Use the Xilinx FPGA_Editor and Timing Analyzer tools to evaluate clock skew specific to your application.

Date	Version	Description of Revisions
02/08/11	2.12	Removed note 1 from Table 4 as the larger devices (XC6VLX550T, XC6VLX760, XC6VSX475T, and XC6VHX565T) are now offered in -2I. Updated Table 4 and Table 5 with data for the XC6VHX380T in the FF(G)1154 package. In Table 41 , updated -1L specification for DDR3. Added Note 1 to Table 42 . Moved the XC6VHX380T devices in the FF(G)1154 package to production release in Table 43 using ISE 12.4 software with current speed specifications. Updated description for F_{INDUTY} in Table 64 .
02/25/11	3.0	Designated the data sheet as Preliminary for all devices not already labeled production in Table 42 . Changed the XC6VHX380T devices in all packages to production status in Table 42 and Table 43 . Removed note 1 from Table 42 . Added maximum specifications to Table 25 . Updated $T_{HAVCC2HAVCCRX}$ in Table 27 . Updated the typical values and notes in Table 28 and Table 29 . Added values to Table 30 and Table 31 . In Table 34 , added values for T_{LOCK} and T_{PHASE} . Updated the values in Table 36 and added note 3. Updated Table 37 and added note 4.
03/21/11	3.1	Updated Table 2 including Note 7 . In Table 4 , added Note 3 and -2E, extended temperature range to the XC6VLX550T, XC6VLX760, XC6VSX475T, and XC6VHX380T devices, and added Note 5 for the XC6VHX565T. Updated Table 28 typical values. Updated the description for $F_{IDELAYCTRL_REF}$ in Table 53 . Updated F_{MCCK} in Table 59 .
04/01/11	3.2	Added T_j values for C, E, and I temperature ranges to Table 2 . Updated the I_{CCQ} values in Table 4 . Updated F_{GCLK} in Table 34 . Designated the data sheet as Production for all devices not already labeled production in Table 42 . Changed the XC6VHX255T and XC6VHX565T devices in all packages to production status in Table 42 and Table 43 . This included updates to the Virtex-6 Device Pin-to-Pin Output Parameter Guidelines and Virtex-6 Device Pin-to-Pin Input Parameter Guidelines for these devices. Production speed specifications for these devices are available using the speed specification v1.14 in the ISE 13.1 software update. Updated and added package skew values to Table 72 ; these values are correct with regards to previous production released speed specifications in software. Updated copyright page 1 and Notice of Disclaimer .
12/08/11	3.3	Production release of the Defense-grade XQ devices in Table 42 and Table 43 using ISE v13.3 v1.17 Patch for -2 and -1 speed specifications; and v1.10 for -1L speed specifications. Added the XQ6VLX130T, XQ6VLX240T, XQ6VLX550T, XQ6VSX315T, and XQ6VSX475T to the data sheet which included adding Table 45 . Updated T_j in Table 2 . In Table 40 , updated T_j for most specifications and added Note 4 . Added Note 4 to Table 41 . Added -1(XQ) speed specification columns only to Table 50 , Table 51 , Table 52 , and Table 58 . Updated V_{OD} in Table 8 , V_{OCM} in Table 9 , and V_{OCM} and V_{DIFF} in Table 10 . Updated the Power-On Power Supply Requirements section. In Table 27 , updated maximum specification for $T_{HAVCC2HAVCCRX}$ and added Note 3 . Updated T_j in Table 40 . In Table 41 , increased the DDR LVDS receiver (SPI-4.2) -1 speed grade performance value from 1.0 Gb/s to 1.1 Gb/s. In Table 60 , updated the F_{MAX} to add a separate row for the LX760 device values. The speed specifications in the software tools have always matched these values for the LX760, the data sheet is now correct. Updated the notes for $T_{OUTJITTER}$ in Table 64 .
01/12/12	3.4	Added the temperature range -2E to Note 5 in Table 4 .

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